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L1	139	703/2.ccls. and @pd>"20070301"	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2007/07/15 14:01

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L8	35	(ramp and weight$1 and state).clm.	US-PGPUB	OR	ON	2007/07/15 15:41

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L2	1218	((mixed adj signal$1) or mixed-signal$1 or hybrid) and (finite adj state)	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2007/07/15 14:48
L4	1155	((analog-digital) or analog/digital or (analog adj digital)) and (finite adj state)	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2007/07/15 14:50

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